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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	13824
Total RAM Bits	110592
Number of I/O	270
Number of Gates	600000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microsemi/agle600v2-fgg484i">https://www.e-xfl.com/product-detail/microsemi/agle600v2-fgg484i</a>

## Pro I/Os with Advanced I/O Standards

The IGLOOe family of FPGAs features a flexible I/O structure, supporting a range of voltages (1.2 V, 1.5 V, 1.8 V, 2.5 V, 3.0 V wide range, and 3.3 V). IGLOOe FPGAs support 19 different I/O standards, including single-ended, differential, and voltage-referenced. The I/Os are organized into banks, with eight banks per device (two per side). The configuration of these banks determines the I/O standards supported. Each I/O bank is subdivided into VREF minibanks, which are used by voltage-referenced I/Os. VREF minibanks contain 8 to 18 I/Os. All the I/Os in a given minibank share a common VREF line. Therefore, if any I/O in a given VREF minibank is configured as a VREF pin, the remaining I/Os in that minibank will be able to use that reference voltage.

Each I/O module contains several input, output, and enable registers. These registers allow the implementation of the following:

- Single-Data-Rate applications (e.g., PCI 66 MHz, bidirectional SSTL 2 and 3, Class I and II)
- Double-Data-Rate applications (e.g., DDR LVDS, B-LVDS, and M-LVDS I/Os for point-to-point communications, and DDR 200 MHz SRAM using bidirectional HSTL Class II).

IGLOOe banks support M-LVDS with 20 multi-drop points.

Hot-swap (also called hot-plug, or hot-insertion) is the operation of hot-insertion or hot-removal of a card in a powered-up system.

Cold-sparing (also called cold-swap) refers to the ability of a device to leave system data undisturbed when the system is powered up, while the component itself is powered down, or when power supplies are floating.

## Wide Range I/O Support

IGLOOe devices support JEDEC-defined wide range I/O operation. IGLOOe devices support both the JESD8-B specification, covering 3.0 V and 3.3 V supplies, for an effective operating range of 2.7 V to 3.6 V, and JESD8-12 with its 1.2 V nominal, supporting an effective operating range of 1.14 V to 1.575 V.

Wider I/O range means designers can eliminate power supplies or power conditioning components from the board or move to less costly components with greater tolerances. Wide range eases I/O bank management and provides enhanced protection from system voltage spikes, while providing the flexibility to easily run custom voltage applications.

## Specifying I/O States During Programming

You can modify the I/O states during programming in FlashPro. In FlashPro, this feature is supported for PDB files generated from Designer v8.5 or greater. See the [FlashPro User's Guide](#) for more information.

**Note:** PDB files generated from Designer v8.1 to Designer v8.4 (including all service packs) have limited display of Pin Numbers only.

1. Load a PDB from the FlashPro GUI. You must have a PDB loaded to modify the I/O states during programming.
2. From the FlashPro GUI, click **PDB Configuration**. A FlashPoint – Programming File Generator window appears.
3. Click the **Specify I/O States During Programming** button to display the Specify I/O States During Programming dialog box.
4. Sort the pins as desired by clicking any of the column headers to sort the entries by that header. Select the I/Os you wish to modify ([Figure 1-4 on page 1-8](#)).
5. Set the I/O Output State. You can set Basic I/O settings if you want to use the default I/O settings for your pins, or use Custom I/O settings to customize the settings for each pin. Basic I/O state settings:
  - 1 – I/O is set to drive out logic High
  - 0 – I/O is set to drive out logic Low
  - Last Known State – I/O is set to the last value that was driven out prior to entering the programming mode, and then held at that value during programming
  - Z -Tri-State: I/O is tristated

- JTAG supply, PLL power supplies, and charge pump VPUMP supply have no influence on I/O behavior.

### PLL Behavior at Brownout Condition

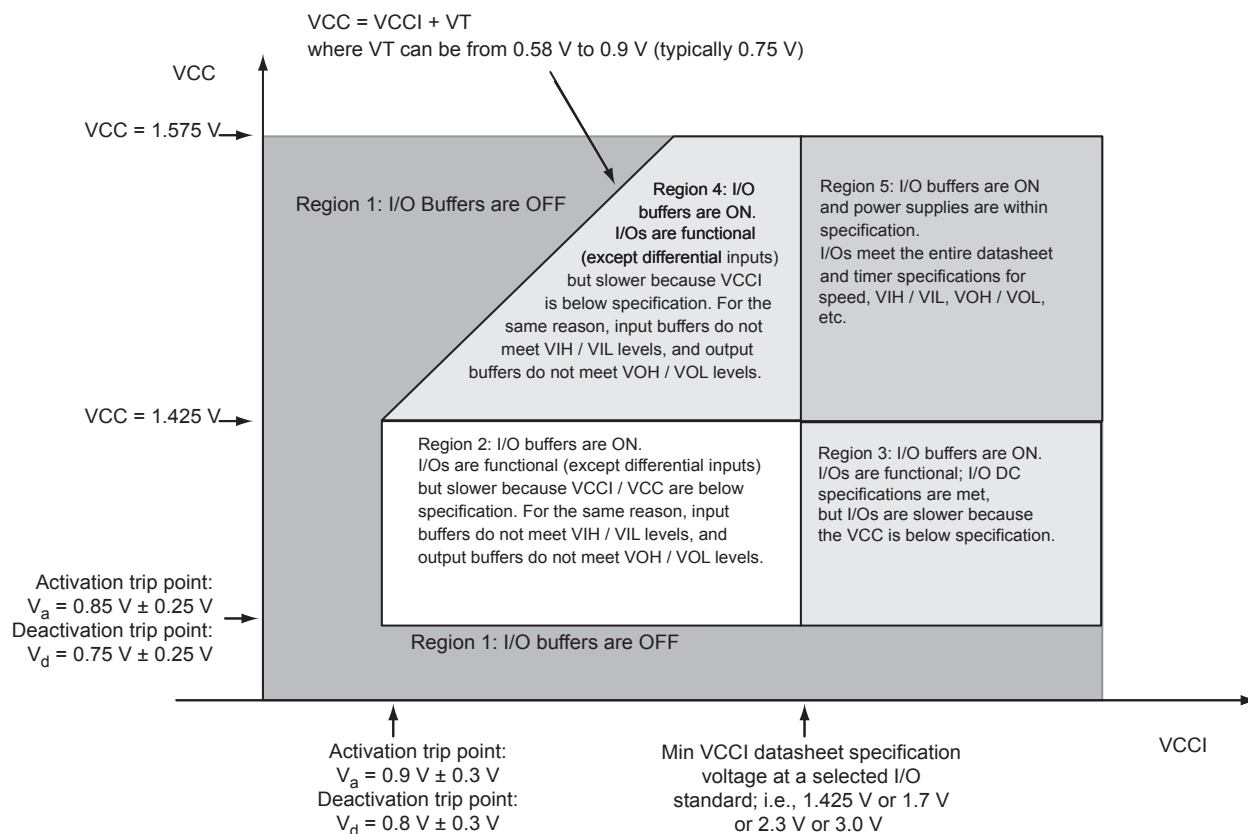
Microsemi recommends using monotonic power supplies or voltage regulators to ensure proper powerup behavior. Power ramp-up should be monotonic at least until VCC and VCCPLX exceed brownout activation levels. The VCC activation level is specified as 1.1 V worst-case (see Figure 2-1 and Figure 2-2 on page 2-5 for more details).

When PLL power supply voltage and/or VCC levels drop below the VCC brownout levels ( $0.75\text{ V} \pm 0.25\text{ V}$ ), the PLL output lock signal goes low and/or the output clock is lost. Refer to the "Power-Up/-Down Behavior of Low Power Flash Devices" chapter of the *IGLOOe FPGA Fabric User's Guide* for information on clock and lock recovery.

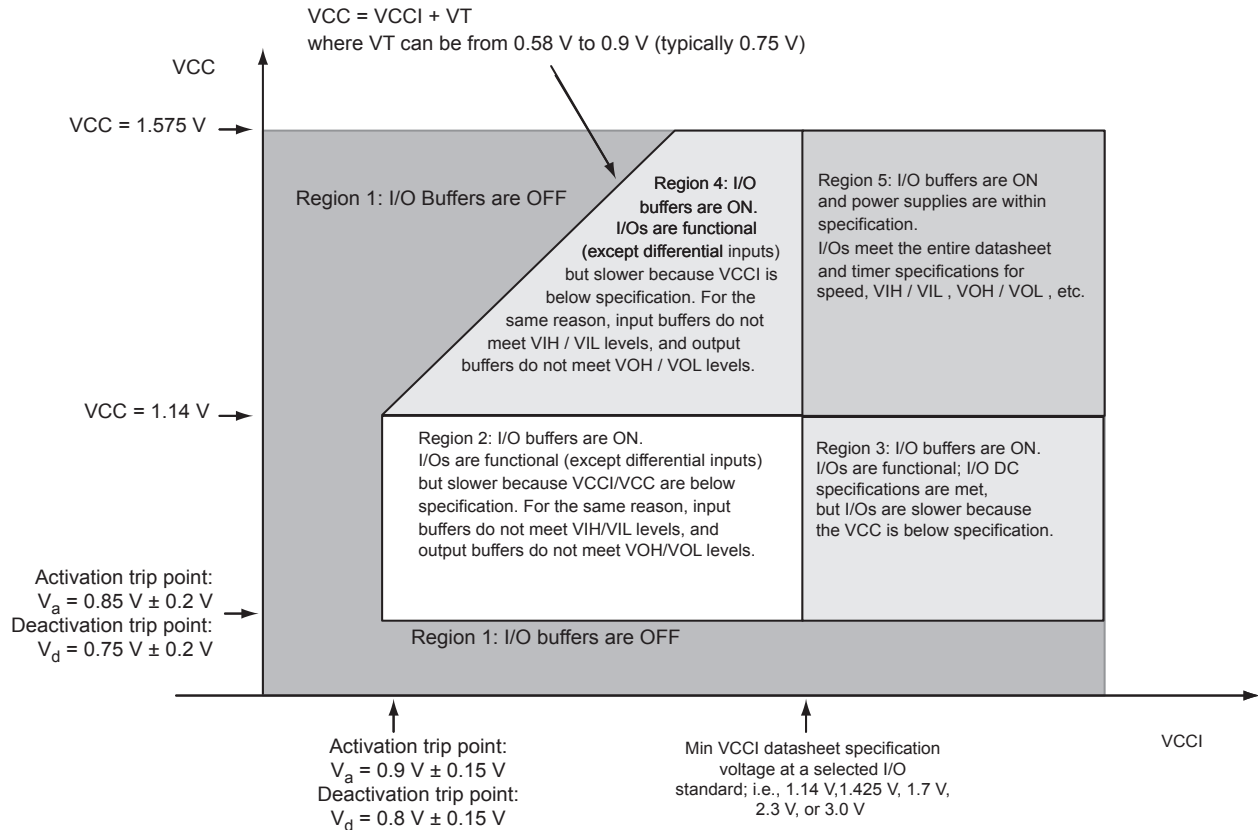
### Internal Power-Up Activation Sequence

1. Core
2. Input buffers

Output buffers, after 200 ns delay from input buffer activation.



**Figure 2-1 • V5 – I/O State as a Function of VCCI and VCC Voltage Levels**



**Figure 2-2 • V2 Devices – I/O State as a Function of VCCI and VCC Voltage Levels**

## Thermal Characteristics

### Introduction

The temperature variable in Microsemi Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because dynamic and static power consumption cause the chip junction to be higher than the ambient temperature.

EQ 1 can be used to calculate junction temperature.

$$T_J = \text{Junction Temperature} = \Delta T + T_A$$

EQ 1

where:

$T_A$  = Ambient Temperature

$\Delta T$  = Temperature gradient between junction (silicon) and ambient  $\Delta T = \theta_{ja} * P$

$\theta_{ja}$  = Junction-to-ambient of the package.  $\theta_{ja}$  numbers are located in [Table 2-5](#).

$P$  = Power dissipation



### 1.2 V DC Core Voltage

**Table 2-50 • 2.5 V LVCMOS Low Slew – Applies to 1.2 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V

Drive Strength	Speed Grade	$t_{DOUT}$	$t_{DP}$	$t_{DIN}$	$t_{PY}$	$t_{PYS}$	$t_{EOUT}$	$t_{ZL}$	$t_{ZH}$	$t_{LZ}$	$t_{HZ}$	$t_{ZLS}$	$t_{ZHS}$	Units
4 mA	Std.	1.55	6.25	0.26	1.55	1.77	1.10	6.36	5.34	2.81	2.63	12.14	11.13	ns
8 mA	Std.	1.55	5.18	0.26	1.55	1.77	1.10	5.26	4.61	3.13	3.32	11.05	10.39	ns
12 mA	Std.	1.55	4.42	0.26	1.55	1.77	1.10	4.49	4.08	3.36	3.76	10.28	9.86	ns
16 mA	Std.	1.55	4.19	0.26	1.55	1.77	1.10	4.25	3.96	3.40	3.89	10.04	9.75	ns
24 mA	Std.	1.55	4.09	0.26	1.55	1.76	1.10	4.15	3.97	3.47	4.32	9.94	9.76	ns

*Note:* For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

**Table 2-51 • 2.5 V LVCMOS High Slew – Applies to 1.2 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V

Drive Strength	Speed Grade	$t_{DOUT}$	$t_{DP}$	$t_{DIN}$	$t_{PY}$	$t_{PYS}$	$t_{EOUT}$	$t_{ZL}$	$t_{ZH}$	$t_{LZ}$	$t_{HZ}$	$t_{ZLS}$	$t_{ZHS}$	Units
4 mA	Std.	1.55	3.38	0.26	1.55	1.77	1.10	3.42	3.11	2.81	2.72	9.21	8.89	ns
8 mA	Std.	1.55	2.83	0.26	1.55	1.77	1.10	2.87	2.51	3.13	3.42	8.66	8.30	ns
12 mA	Std.	1.55	2.51	0.26	1.55	1.77	1.10	2.54	2.22	3.36	3.85	8.33	8.00	ns
16 mA	Std.	1.55	2.45	0.26	1.55	1.77	1.10	2.48	2.16	3.40	3.97	8.27	7.95	ns
24 mA	Std.	1.55	2.46	0.26	1.55	1.77	1.10	2.49	2.09	3.47	4.44	8.28	7.88	ns

*Notes:*

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

## Timing Characteristics

### 1.5 V DC Core Voltage

**Table 2-54 • 1.8 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.7 V

Drive Strength	Speed Grade	$t_{DOUT}$	$t_{DP}$	$t_{DIN}$	$t_{PY}$	$t_{PYS}$	$t_{EOUT}$	$t_{ZL}$	$t_{ZH}$	$t_{LZ}$	$t_{HZ}$	$t_{ZLS}$	$t_{ZHS}$	Units
2 mA	Std.	0.97	7.33	0.18	1.27	1.59	0.66	7.47	6.18	2.34	1.18	11.07	9.77	ns
4 mA	Std.	0.97	6.07	0.18	1.27	1.59	0.66	6.20	5.25	2.69	2.42	9.79	8.84	ns
6 mA	Std.	0.97	5.18	0.18	1.27	1.59	0.66	5.29	4.61	2.93	2.88	8.88	8.21	ns
8 mA	Std.	0.97	4.88	0.18	1.27	1.59	0.66	4.98	4.48	2.99	3.01	8.58	8.08	ns
12 mA	Std.	0.97	4.80	0.18	1.27	1.59	0.66	4.89	4.49	3.07	3.47	8.49	8.09	ns
16 mA	Std.	0.97	4.80	0.18	1.27	1.59	0.66	4.89	4.49	3.07	3.47	8.49	8.09	ns

*Note:* For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

**Table 2-55 • 1.8 V LVCMOS High Slew – Applies to 1.5 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.7 V

Drive Strength	Speed Grade	$t_{DOUT}$	$t_{DP}$	$t_{DIN}$	$t_{PY}$	$t_{PYS}$	$t_{EOUT}$	$t_{ZL}$	$t_{ZH}$	$t_{LZ}$	$t_{HZ}$	$t_{ZLS}$	$t_{ZHS}$	Units
2 mA	Std.	0.97	3.43	0.18	1.27	1.59	0.66	3.51	3.39	2.33	1.19	7.10	6.98	ns
4 mA	Std.	0.97	2.83	0.18	1.27	1.59	0.66	2.89	2.59	2.69	2.49	6.48	6.18	ns
6 mA	Std.	0.97	2.45	0.18	1.27	1.59	0.66	2.51	2.19	2.93	2.95	6.10	5.79	ns
8 mA	Std.	0.97	2.38	0.18	1.27	1.59	0.66	2.43	2.12	2.98	3.08	6.03	5.71	ns
12 mA	Std.	0.97	2.37	0.18	1.27	1.59	0.66	2.42	2.03	3.07	3.57	6.02	5.62	ns
16 mA	Std.	0.97	2.37	0.18	1.27	1.59	0.66	2.42	2.03	3.07	3.57	6.02	5.62	ns

*Notes:*

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

## 1.5 V LVCMOS (JESD8-11)

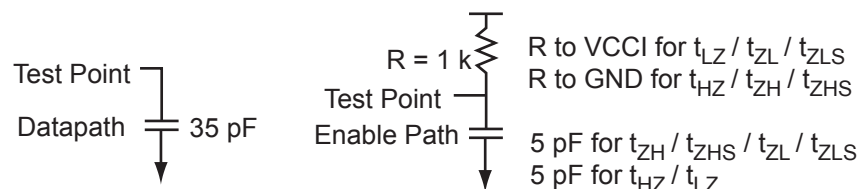
Low-Voltage CMOS for 1.5 V is an extension of the LVCMOS standard (JESD8-5) used for general-purpose 1.5 V applications. It uses a 1.5 V input buffer and a push-pull output buffer.

**Table 2-58 • Minimum and Maximum DC Input and Output Levels**

1.5 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
2 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	2	2	13	16	10	10
4 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	4	4	25	33	10	10
6 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	6	6	32	39	10	10
8 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	8	8	66	55	10	10
12 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	12	12	66	55	10	10

**Notes:**

1. IIL is the input leakage current per I/O pin over recommended operation conditions where  $-0.3\text{ V} < V_{IN} < V_{IL}$ .
2. IIH is the input leakage current per I/O pin over recommended operating conditions  $V_{IH} < V_{IN} < V_{CCI}$ . Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.
5. Software default selection highlighted in gray.



**Figure 2-10 • AC Loading**

**Table 2-59 • AC Waveforms, Measuring Points, and Capacitive Loads**

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	C <sub>LOAD</sub> (pF)
0	1.5	0.75	—	5

**Note:** \*Measuring point = Vtrip. See [Table 2-23 on page 2-23](#) for a complete table of trip points.

## 2.5 V GTL

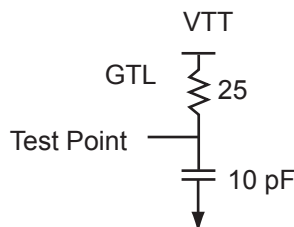
Gunning Transceiver Logic is a high-speed bus standard (JESD8-3). It provides a differential amplifier input buffer and an open-drain output buffer. The VCCI pin should be connected to 2.5 V.

**Table 2-77 • Minimum and Maximum DC Input and Output Levels**

2.5 GTL	VIL		VIH		VOL	VOH	IOL	IOH	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
20 mA <sup>5</sup>	−0.3	VREF − 0.05	VREF + 0.05	3.6	0.4	−	20	20	169	124	10	10

**Notes:**

1. IIL is the input leakage current per I/O pin over recommended operating conditions where  $-0.3\text{ V} < V_{IN} < V_{IL}$ .
2. IIH is the input leakage current per I/O pin over recommended operating conditions  $V_{IH} < V_{IN} < V_{CCI}$ . Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.
5. Output drive strength is below JEDEC specification.



**Figure 2-14 • AC Loading**

**Table 2-78 • AC Waveforms, Measuring Points, and Capacitive Loads**

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C <sub>LOAD</sub> (pF)
VREF − 0.05	VREF + 0.05	0.8	0.8	1.2	10

**Note:** \*Measuring point = Vtrip. See Table 2-23 on page 2-23 for a complete table of trip points.

## Timing Characteristics

### 1.5 V DC Core Voltage

**Table 2-79 • 2.5 V GTL – Applies to 1.5 V DC Core Voltage**  
Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V,  
Worst-Case VCCI = 3.0 V VREF = 0.8 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	0.98	1.90	0.19	2.04	0.67	1.94	1.87			5.57	5.50	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

### 1.2 V DC Core Voltage

**Table 2-80 • 2.5 V GTL – Applies to 1.2 V DC Core Voltage**  
Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.14 V,  
Worst-Case VCCI = 3.0 V VREF = 0.8 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	1.55	2.16	0.26	2.35	1.10	2.20	2.13			8.01	7.94	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-6 for derating values.

## 2.5 V GTL+

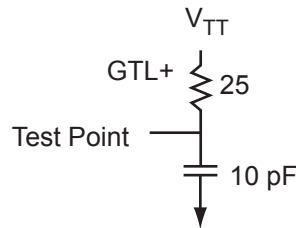
Gunning Transceiver Logic Plus is a high-speed bus standard (JESD8-3). It provides a differential amplifier input buffer and an open-drain output buffer. The VCCI pin should be connected to 2.5 V.

**Table 2-85 • Minimum and Maximum DC Input and Output Levels**

2.5 V GTL+	VIL		VIH		VOL	VOH	IOL	IOH	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
33 mA	-0.3	VREF - 0.1	VREF + 0.1	3.6	0.6	-	33	33	169	124	10	10

**Notes:**

1. IIL is the input leakage current per I/O pin over recommended operating conditions where  $-0.3\text{ V} < V_{IN} < V_{IL}$ .
2. IIH is the input leakage current per I/O pin over recommended operating conditions  $V_{IH} < V_{IN} < V_{CCI}$ . Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.



**Figure 2-16 • AC Loading**

**Table 2-86 • AC Waveforms, Measuring Points, and Capacitive Loads**

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C <sub>LOAD</sub> (pF)
VREF - 0.1	VREF + 0.1	1.0	1.0	1.5	10

**Note:** \*Measuring point = Vtrip. See Table 2-23 on page 2-23 for a complete table of trip points.

### Timing Characteristics

#### 1.5 V DC Core Voltage

**Table 2-87 • 2.5 V GTL+ – Applies to 1.5 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.425 V,  
Worst-Case VCCI = 2.3 V VREF = 1.0 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	0.98	1.97	0.19	1.29	0.67	2.00	1.84			5.63	5.47	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

#### 1.2 V DC Core Voltage

**Table 2-88 • 2.5 V GTL+ – Applies to 1.2 V DC Core Voltage**

Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.14 V,  
Worst-Case VCCI = 2.3 V VREF = 1.0 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	1.55	2.23	0.26	1.55	1.10	2.28	2.11			8.08	7.91	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-6 for derating values.

## HSTL Class I

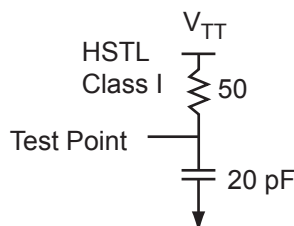
High-Speed Transceiver Logic is a general-purpose high-speed 1.5 V bus standard (EIA/JESD8-6). IGLOOe devices support Class I. This provides a differential amplifier input buffer and a push-pull output buffer.

**Table 2-89 • Minimum and Maximum DC Input and Output Levels**

HSTL Class I	VIL		VIH		VOL	VOH	IOL	IOH	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
8 mA	-0.3	VREF - 0.1	VREF + 0.1	3.6	0.4	VCCI - 0.4	8	8	32	39	10	10

**Notes:**

1. IIL is the input leakage current per I/O pin over recommended operating conditions where  $-0.3\text{ V} < V_{IN} < V_{IL}$ .
2. IIH is the input leakage current per I/O pin over recommended operating conditions  $V_{IH} < V_{IN} < V_{CCI}$ . Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.



**Figure 2-17 • AC Loading**

**Table 2-90 • AC Waveforms, Measuring Points, and Capacitive Loads**

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C <sub>LOAD</sub> (pF)
VREF - 0.1	VREF + 0.1	0.75	0.75	0.75	20

**Note:** \*Measuring point =  $V_{trip}$ . See Table 2-23 on page 2-23 for a complete table of trip points.

## Timing Characteristics

### 1.5 V DC Core Voltage

**Table 2-91 • HSTL Class I – Applies to 1.5 V DC Core Voltage**  
Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.425 V,  
Worst-Case VCCI = 1.4 V VREF = 0.75 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	0.98	2.74	0.19	1.77	0.67	2.79	2.73			6.42	6.36	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

### 1.2 V DC Core Voltage

**Table 2-92 • HSTL Class I – Applies to 1.2 V DC Core Voltage**  
Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.14 V,  
Worst-Case VCCI = 1.4 V VREF = 0.75 V

Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
Std.	1.55	3.10	0.26	1.94	1.10	3.12	3.10			8.93	8.91	ns

**Note:** For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-6 for derating values.

## Timing Characteristics

### 1.5 V DC Core Voltage

**Table 2-133 • Output DDR Propagation Delays**  
Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case  $V_{CC} = 1.425\text{ V}$

Parameter	Description	Std.	Units
$t_{\text{DDROCLKQ}}$	Clock-to-Out of DDR for Output DDR	1.07	ns
$t_{\text{DDROSUD1}}$	Data_F Data Setup for Output DDR	0.67	ns
$t_{\text{DDROSUD2}}$	Data_R Data Setup for Output DDR	0.67	ns
$t_{\text{DDROHD1}}$	Data_F Data Hold for Output DDR	0.00	ns
$t_{\text{DDROHD2}}$	Data_R Data Hold for Output DDR	0.00	ns
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out for Output DDR	1.38	ns
$t_{\text{DDROREMCLR}}$	Asynchronous Clear Removal Time for Output DDR	0.00	ns
$t_{\text{DDRORECCLR}}$	Asynchronous Clear Recovery Time for Output DDR	0.23	ns
$t_{\text{DDROWCLR1}}$	Asynchronous Clear Minimum Pulse Width for Output DDR	0.19	ns
$t_{\text{DDROCKMPWH}}$	Clock Minimum Pulse Width HIGH for the Output DDR	0.31	ns
$t_{\text{DDROCKMPWL}}$	Clock Minimum Pulse Width LOW for the Output DDR	0.28	ns
$F_{\text{DDOMAX}}$	Maximum Frequency for the Output DDR	250.00	MHz

*Note:* For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

### 1.2 V DC Core Voltage

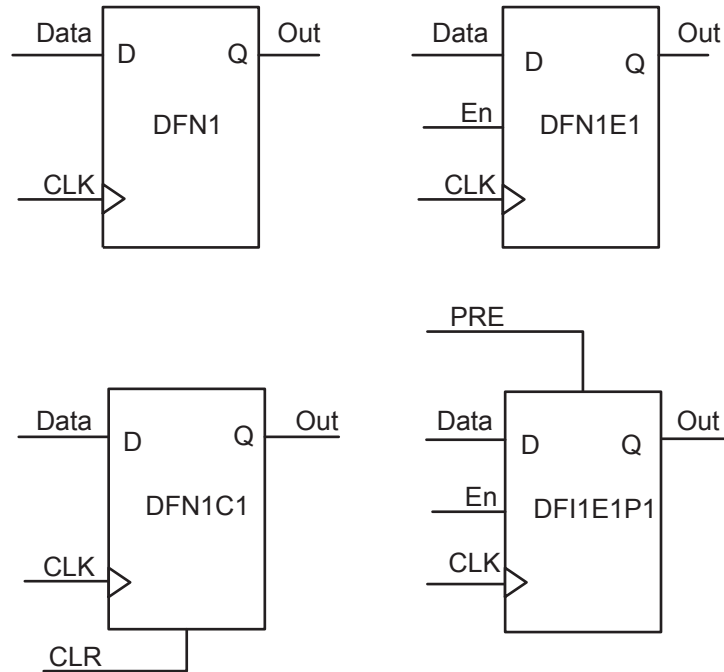
**Table 2-134 • Output DDR Propagation Delays**  
Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case  $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.	Units
$t_{\text{DDROCLKQ}}$	Clock-to-Out of DDR for Output DDR	1.60	ns
$t_{\text{DDROSUD1}}$	Data_F Data Setup for Output DDR	1.09	ns
$t_{\text{DDROSUD2}}$	Data_R Data Setup for Output DDR	1.16	ns
$t_{\text{DDROHD1}}$	Data_F Data Hold for Output DDR	0.00	ns
$t_{\text{DDROHD2}}$	Data_R Data Hold for Output DDR	0.00	ns
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out for Output DDR	1.99	ns
$t_{\text{DDROREMCLR}}$	Asynchronous Clear Removal Time for Output DDR	0.00	ns
$t_{\text{DDRORECCLR}}$	Asynchronous Clear Recovery Time for Output DDR	0.24	ns
$t_{\text{DDROWCLR1}}$	Asynchronous Clear Minimum Pulse Width for Output DDR	0.19	ns
$t_{\text{DDROCKMPWH}}$	Clock Minimum Pulse Width HIGH for the Output DDR	0.31	ns
$t_{\text{DDROCKMPWL}}$	Clock Minimum Pulse Width LOW for the Output DDR	0.28	ns
$F_{\text{DDOMAX}}$	Maximum Frequency for the Output DDR	160.00	MHz

*Note:* For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

## VersaTile Specifications as a Sequential Module

The IGLOOe library offers a wide variety of sequential cells, including flip-flops and latches. Each has a data input and optional enable, clear, or preset. In this section, timing characteristics are presented for a representative sample from the library. For more details, refer to the [IGLOO](#), [Fusion](#), and [ProASIC3 Macro Library Guide](#).



**Figure 2-37 • Sample of Sequential Cells**



## Embedded SRAM and FIFO Characteristics

### SRAM

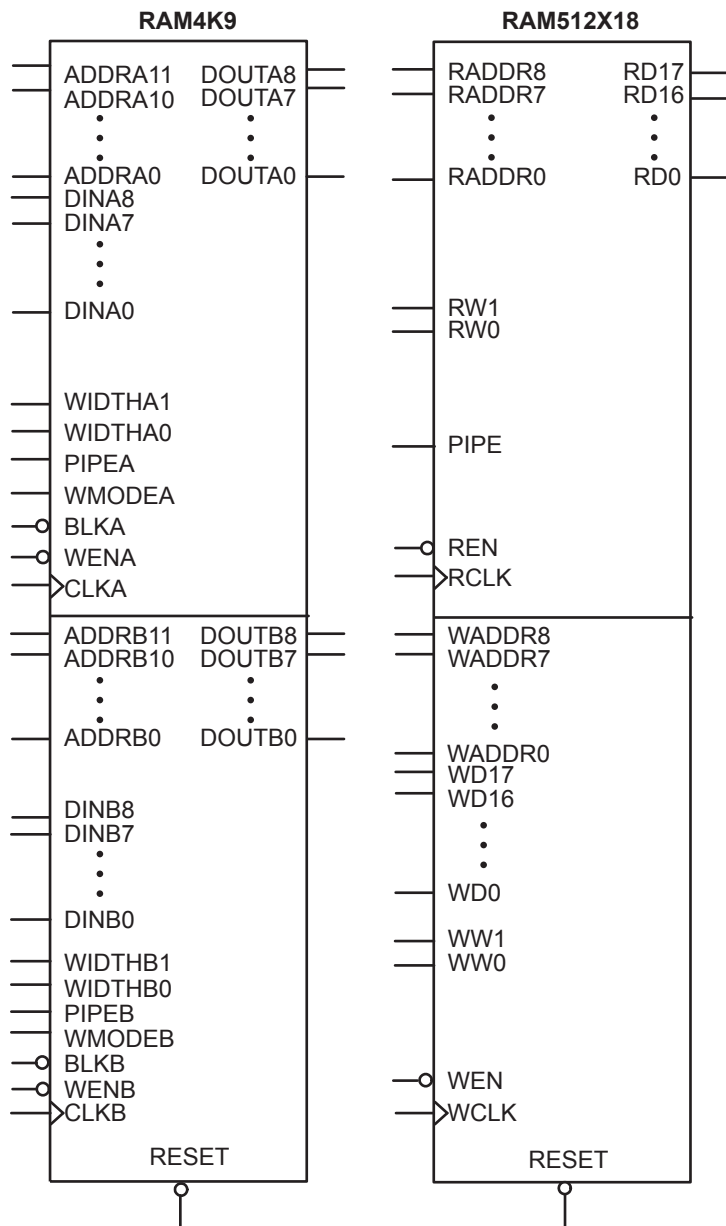


Figure 2-41 • RAM Models

**Applies to 1.2 V DC Core Voltage**

**Table 2-147 • RAM4K9**

**Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case  $V_{CC} = 1.14\text{ V}$**

Parameter	Description	Std.	Units
$t_{AS}$	Address Setup Time	1.53	ns
$t_{AH}$	Address Hold Time	0.29	ns
$t_{ENS}$	REN, WEN Setup Time	1.50	ns
$t_{ENH}$	REN, WEN Hold Time	0.29	ns
$t_{BKS}$	BLK Setup Time	3.05	ns
$t_{BKH}$	BLK Hold Time	0.29	ns
$t_{DS}$	Input Data (DIN) Setup Time	1.33	ns
$t_{DH}$	Input Data (DIN) Hold Time	0.66	ns
$t_{CKQ1}$	Clock High to New Data Valid on DOUT (output retained, WMODE = 0)	6.61	ns
	Clock High to New Data Valid on DOUT (flow-through, WMODE = 1)	5.72	ns
$t_{CKQ2}$	Clock High to New Data Valid on DOUT (pipelined)	3.38	ns
$t_{C2CWWL}^1$	Address collision clk-to-clk delay for reliable write after write on same address; applicable to closing edge	0.30	ns
$t_{C2CRWH}^1$	Address collision clk-to-clk delay for reliable read access after write on same address; applicable to opening edge	0.89	ns
$t_{C2CWRH}^1$	Address collision clk-to-clk delay for reliable write access after read on same address; applicable to opening edge	1.01	ns
$t_{RSTBQ}$	RESET Low to Data Out Low on DOUT (pass-through)	3.86	ns
	RESET Low to Data Out Low on DOUT (pipelined)	3.86	ns
$t_{REMRSTB}$	RESET Removal	1.12	ns
$t_{RECRSTB}$	RESET Recovery	5.93	ns
$t_{MPWRSTB}$	RESET Minimum Pulse Width	1.18	ns
$t_{CYC}$	Clock Cycle Time	10.90	ns
$F_{MAX}$	Maximum Frequency	92	MHz

**Notes:**

1. For more information, refer to the application note [Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs](#).
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

**Table 2-148 • RAM512X18**
**Commercial-Case Conditions:  $T_J = 70^{\circ}\text{C}$ , Worst-Case  $V_{CC} = 1.14\text{ V}$** 

Parameter	Description	Std.	Units
$t_{AS}$	Address Setup Time	1.53	ns
$t_{AH}$	Address Hold Time	0.29	ns
$t_{ENS}$	REN, WEN Setup Time	1.36	ns
$t_{ENH}$	REN, WEN Hold Time	0.15	ns
$t_{DS}$	Input Data (WD) Setup Time	1.33	ns
$t_{DH}$	Input Data (WD) Hold Time	0.66	ns
$t_{CKQ1}$	Clock High to New Data Valid on RD (output retained)	7.88	ns
$t_{CKQ2}$	Clock High to New Data Valid on RD (pipelined)	3.20	ns
$t_{C2CRWH}^1$	Address collision clk-to-clk delay for reliable read access after write on same address; applicable to opening edge	0.87	ns
$t_{C2CWRH}^1$	Address collision clk-to-clk delay for reliable write access after read on same address; applicable to opening edge	1.04	ns
$t_{RSTBQ}$	RESET Low to Data Out Low on RD (flow-through)	3.86	ns
	RESET Low to Data Out Low on RD (pipelined)	3.86	ns
$t_{REMRSTB}$	RESET Removal	1.12	ns
$t_{RECRSTB}$	RESET Recovery	5.93	ns
$t_{MPWRSTB}$	RESET Minimum Pulse Width	1.18	ns
$t_{CYC}$	Clock Cycle Time	10.90	ns
$F_{MAX}$	Maximum Frequency	92	MHz

**Notes:**

1. For more information, refer to the application note [Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs](#).
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.



FG484		FG484		FG484	
Pin Number	AGLE600 Function	Pin Number	AGLE600 Function	Pin Number	AGLE600 Function
N8	VCCIB6	P21	IO59PDB3V0	T12	IO82NDB5V0
N9	VCC	P22	IO58NDB3V0	T13	IO74NDB4V1
N10	GND	R1	NC	T14	IO74PDB4V1
N11	GND	R2	IO110PDB6V0	T15	GNDQ
N12	GND	R3	VCC	T16	VCOMPLD
N13	GND	R4	IO109NPB6V0	T17	VJTAG
N14	VCC	R5	IO106NDB6V0	T18	GDC0/IO65NDB3V1
N15	VCCIB3	R6	IO106PDB6V0	T19	GDA1/IO67PDB3V1
N16	IO54NPB3V0	R7	GEC0/IO104NPB6V0	T20	NC
N17	IO57NPB3V0	R8	VMV5	T21	IO64PDB3V1
N18	IO55NPB3V0	R9	VCCIB5	T22	IO62NDB3V1
N19	IO57PPB3V0	R10	VCCIB5	U1	NC
N20	NC	R11	IO84NDB5V0	U2	IO107PDB6V0
N21	IO56NDB3V0	R12	IO84PDB5V0	U3	IO107NDB6V0
N22	IO58PDB3V0	R13	VCCIB4	U4	GEB1/IO103PDB6V0
P1	NC	R14	VCCIB4	U5	GEB0/IO103NDB6V0
P2	IO111PDB6V1	R15	VMV3	U6	VMV6
P3	IO115NPB6V1	R16	VCCPLD	U7	VCCPLE
P4	IO113NPB6V1	R17	GDB1/IO66PPB3V1	U8	IO101NPB5V2
P5	IO109PPB6V0	R18	GDC1/IO65PDB3V1	U9	IO95PPB5V1
P6	IO108PDB6V0	R19	IO61NDB3V1	U10	IO92PDB5V1
P7	IO108NDB6V0	R20	VCC	U11	IO90PDB5V1
P8	VCCIB6	R21	IO59NDB3V0	U12	IO82PDB5V0
P9	GND	R22	IO62PDB3V1	U13	IO76NDB4V1
P10	VCC	T1	NC	U14	IO76PDB4V1
P11	VCC	T2	IO110NDB6V0	U15	VMV4
P12	VCC	T3	NC	U16	TCK
P13	VCC	T4	IO105PDB6V0	U17	VPUMP
P14	GND	T5	IO105NDB6V0	U18	TRST
P15	VCCIB3	T6	GEC1/IO104PPB6V0	U19	GDA0/IO67NDB3V1
P16	GDB0/IO66NPB3V1	T7	VCOMPLE	U20	NC
P17	IO60NDB3V1	T8	GNDQ	U21	IO64NDB3V1
P18	IO60PDB3V1	T9	GEA2/IO101PPB5V2	U22	IO63PDB3V1
P19	IO61PDB3V1	T10	IO92NDB5V1	V1	NC
P20	NC	T11	IO90NDB5V1	V2	NC

FG484	
Pin Number	AGLE3000 Function
H13	VCCIB1
H14	VCCIB1
H15	VMV1
H16	GBC2/IO84PDB2V0
H17	IO83NDB2V0
H18	IO100NDB2V2
H19	IO100PDB2V2
H20	VCC
H21	VMV2
H22	IO105PDB2V2
J1	IO285NDB7V1
J2	IO285PDB7V1
J3	VMV7
J4	IO279PDB7V0
J5	IO283PDB7V1
J6	IO281PDB7V0
J7	IO287NDB7V1
J8	VCCIB7
J9	GND
J10	VCC
J11	VCC
J12	VCC
J13	VCC
J14	GND
J15	VCCIB2
J16	IO84NDB2V0
J17	IO104NDB2V2
J18	IO104PDB2V2
J19	IO106PPB2V3
J20	GNDQ
J21	IO109PDB2V3
J22	IO107PDB2V3
K1	IO277NDB7V0
K2	IO277PDB7V0
K3	GNDQ

FG484	
Pin Number	AGLE3000 Function
K4	IO279NDB7V0
K5	IO283NDB7V1
K6	IO281NDB7V0
K7	GFC1/IO275PPB7V0
K8	VCCIB7
K9	VCC
K10	GND
K11	GND
K12	GND
K13	GND
K14	VCC
K15	VCCIB2
K16	GCC1/IO112PPB2V3
K17	IO108NDB2V3
K18	IO108PDB2V3
K19	IO110NPB2V3
K20	IO106NPB2V3
K21	IO109NDB2V3
K22	IO107NDB2V3
L1	IO257PSB6V2
L2	IO276PDB7V0
L3	IO276NDB7V0
L4	GFB0/IO274NPB7V0
L5	GFA0/IO273NDB6V4
L6	GFB1/IO274PPB7V0
L7	VCOMPLF
L8	GFC0/IO275NPB7V0
L9	VCC
L10	GND
L11	GND
L12	GND
L13	GND
L14	VCC
L15	GCC0/IO112NPB2V3
L16	GCB1/IO113PPB2V3

FG484	
Pin Number	AGLE3000 Function
L17	GCA0/IO114NPB3V0
L18	VCOMPLC
L19	GCB0/IO113NPB2V3
L20	IO110PPB2V3
L21	IO111NDB2V3
L22	IO111PDB2V3
M1	GNDQ
M2	IO255NPB6V2
M3	IO272NDB6V4
M4	GFA2/IO272PDB6V4
M5	GFA1/IO273PDB6V4
M6	VCCPLF
M7	IO271NDB6V4
M8	GFB2/IO271PDB6V4
M9	VCC
M10	GND
M11	GND
M12	GND
M13	GND
M14	VCC
M15	GCB2/IO116PPB3V0
M16	GCA1/IO114PPB3V0
M17	GCC2/IO117PPB3V0
M18	VCCPLC
M19	GCA2/IO115PDB3V0
M20	IO115NDB3V0
M21	IO126PDB3V1
M22	IO124PSB3V1
N1	IO255PPB6V2
N2	IO253NDB6V2
N3	VMV6
N4	GFC2/IO270PPB6V4
N5	IO261PPB6V3
N6	IO263PDB6V3
N7	IO263NDB6V3

FG896	
Pin Number	AGLE3000 Function
AK14	IO197PDB5V0
AK15	IO191NDB4V4
AK16	IO191PDB4V4
AK17	IO189NDB4V4
AK18	IO189PDB4V4
AK19	IO179PPB4V3
AK20	IO175NDB4V2
AK21	IO175PDB4V2
AK22	IO169NDB4V1
AK23	IO169PDB4V1
AK24	GND
AK25	IO167PPB4V1
AK26	GND
AK27	GDC2/IO156PPB4V0
AK28	GND
AK29	GND
B1	GND
B2	GND
B3	GAA2/IO309PPB7V4
B4	VCC
B5	IO14PPB0V1
B6	VCC
B7	IO07PPB0V0
B8	IO09PDB0V1
B9	IO15PPB0V1
B10	IO19NDB0V2
B11	IO19PDB0V2
B12	IO29NDB0V3
B13	IO29PDB0V3
B14	IO31PPB0V3
B15	IO37NDB0V4
B16	IO37PDB0V4
B17	IO41PDB1V0
B18	IO51NDB1V1
B19	IO59PDB1V2

FG896	
Pin Number	AGLE3000 Function
B20	IO53PDB1V1
B21	IO53NDB1V1
B22	IO61NDB1V2
B23	IO61PDB1V2
B24	IO69NPB1V3
B25	VCC
B26	GBC0/IO79NPB1V4
B27	VCC
B28	IO64NPB1V2
B29	GND
B30	GND
C1	GND
C2	IO309NPB7V4
C3	VCC
C4	GAA0/IO00NPB0V0
C5	VCCIB0
C6	IO03PDB0V0
C7	IO03NDB0V0
C8	GAB1/IO01PDB0V0
C9	IO05PDB0V0
C10	IO15NPB0V1
C11	IO25NDB0V3
C12	IO25PDB0V3
C13	IO31NPB0V3
C14	IO27NDB0V3
C15	IO39NDB0V4
C16	IO39PDB0V4
C17	IO55PPB1V1
C18	IO51PDB1V1
C19	IO59NDB1V2
C20	IO63NDB1V2
C21	IO63PDB1V2
C22	IO67NDB1V3
C23	IO67PDB1V3
C24	IO75NDB1V4

FG896	
Pin Number	AGLE3000 Function
C25	IO75PDB1V4
C26	VCCIB1
C27	IO64PPB1V2
C28	VCC
C29	GBA1/IO81PPB1V4
C30	GND
D1	IO303PPB7V3
D2	VCC
D3	IO305NPB7V3
D4	GND
D5	GAA1/IO00PPB0V0
D6	GAC1/IO02PDB0V0
D7	IO06NPB0V0
D8	GAB0/IO01NDB0V0
D9	IO05NDB0V0
D10	IO11NDB0V1
D11	IO11PDB0V1
D12	IO23NDB0V2
D13	IO23PDB0V2
D14	IO27PDB0V3
D15	IO40PDB0V4
D16	IO47NDB1V0
D17	IO47PDB1V0
D18	IO55NPB1V1
D19	IO65NDB1V3
D20	IO65PDB1V3
D21	IO71NDB1V3
D22	IO71PDB1V3
D23	IO73NDB1V4
D24	IO73PDB1V4
D25	IO74NDB1V4
D26	GBB0/IO80NPB1V4
D27	GND
D28	GBA0/IO81NPB1V4
D29	VCC





